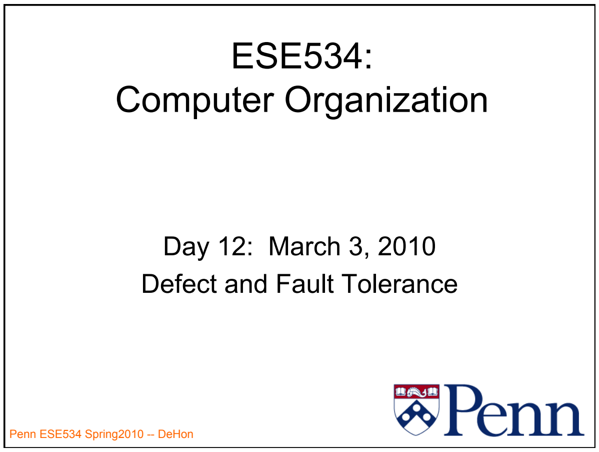
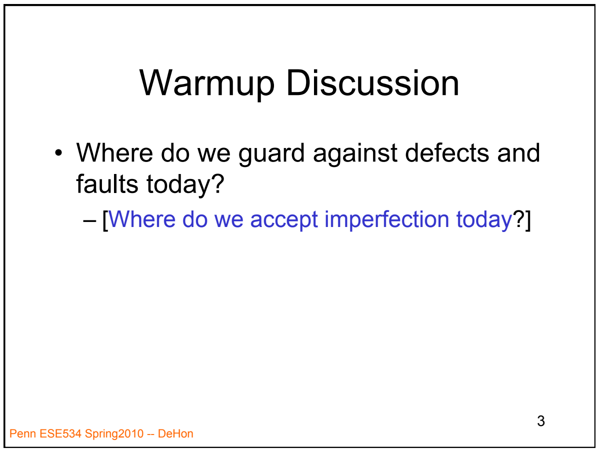


ESE534:
Computer Organization

Day 12: March 3, 2010
Defect and Fault Tolerance

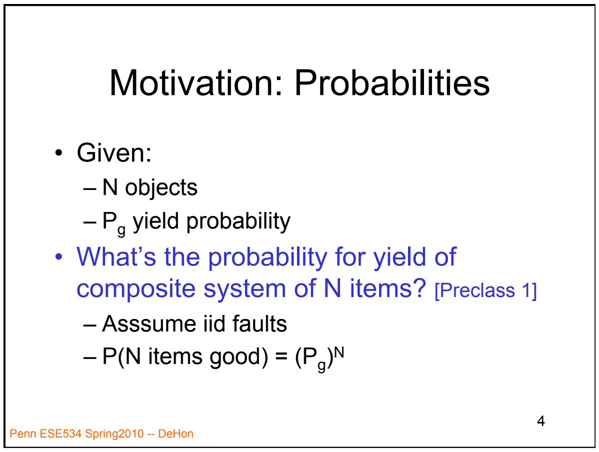
Today

- Defect and Fault Tolerance
  - Problem
  - Defect Tolerance
  - Fault Tolerance



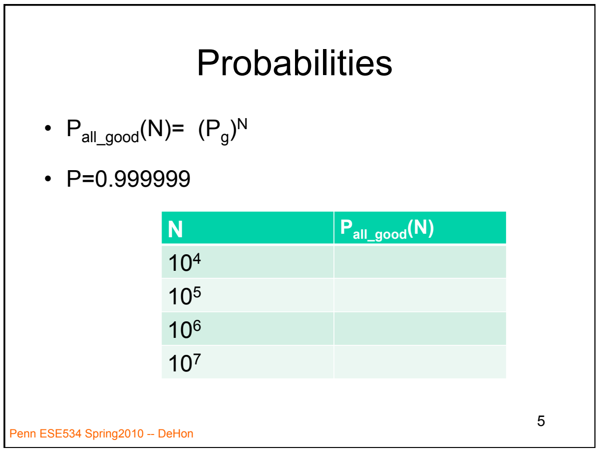
Warmup Discussion

- Where do we guard against defects and faults today?
  - [Where do we accept imperfection today?]



Motivation: Probabilities

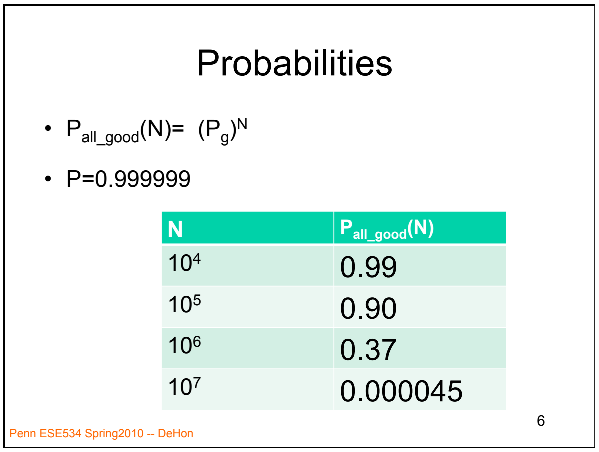
- Given:
  - N objects
  - P_g yield probability
- What's the probability for yield of composite system of N items? [Preclass 1]
  - Asssume iid faults
  - P(N items good) = $(P_g)^N$



Probabilities

- $P_{all\_good}(N) = (P_g)^N$
- P=0.999999

N	$P_{all\_good}(N)$
10^4	
10^5	
10^6	
10^7	



Probabilities

- $P_{all\_good}(N) = (P_g)^N$
- P=0.999999

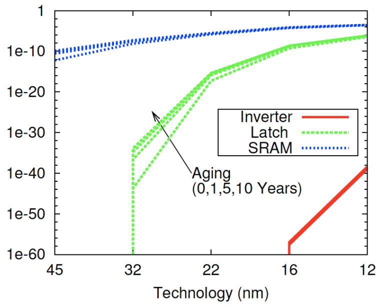
N	$P_{all\_good}(N)$
10^4	0.99
10^5	0.90
10^6	0.37
10^7	0.000045

Simple Implications

- As N gets large
  - must either increase reliability
  - …or start tolerating failures
- N
  - memory bits
  - disk sectors
  - wires
  - transmitted data bits
  - processors
  - transistors
  - molecules

- As devices get smaller, failure rates increase
- chemists think P=0.95 is good
- As devices get faster, failure rate increases

Failure Rate Increases



[Nassif / DATE 2010]

Quality Required for Perfection?

- How high must P_g be to achieve 90% yield on a collection of 10^{10} devices?

[preclass 3]

$$\left(P_g\right)^{10^{10}} > 0.9$$

$P_g > 1-10^{-11}$

Defining Problems

Three Problems

1. **Defects:** Manufacturing imperfection
   - Occur before operation; persistent
     - Shorts, breaks, bad contact
2. **Transient Faults:**
   - Occur during operation; transient
     - node X value flips: crosstalk, ionizing particles, bad timing, tunneling, thermal noise
3. **Lifetime "wear" defects**
   - Parts become bad during operational lifetime
     - Fatigue, electromigration, burnout….
   - …slower
     - NBTI, Hot Carrier Injection

Defects

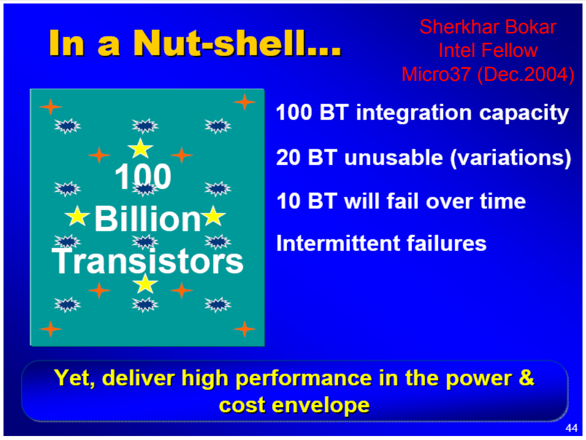
- Shorts example of defect
- Persistent problem
  - reliably manifests
- Occurs before computation
- Can test for at fabrication / boot time and then avoid
- (1st half of lecture)

Faults

- Alpha particle bit flips is an example of a fault
- Fault occurs dynamically during execution
- At any point in time, can fail
  - (produce the wrong result)
- (2nd half of lecture)

Lifetime Wear

- Starts out fine
- Over time changes
  - *E.g.* resistance increases until out of spec.
- Persistent
  - So can use defect techniques to avoid
- But, onset is dynamic
  - Must use fault detection techniques to recognize?



In a Nut-shell…

Sherkhar Bokar
Intel Fellow
Micro37 (Dec.2004)

100 BT integration capacity

20 BT unusable (variations)

10 BT will fail over time

Intermittent failures

Yet, deliver high performance in the power & cost envelope

Defect Rate

- Device with 10^{11} elements (100BT)
- 3 year lifetime = 10^8 seconds
- Accumulating up to 10% defects
- 10^{10} defects in 10^8 seconds
  →1 new defect every 10ms
- At 10GHz operation:
  - One new defect every 10^8 cycles
  - $P_{newdefect}=10^{-19}$

First Step to Recover

Admit you have a problem

(observe that there is a failure)

Detection

- How do we determine if something wrong?
  - Some things easy
    - ….won't start
  - Others tricky
    - …one **and** gate computes False & True→True
- Observability
  - can see effect of problem
  - some way of telling if defect/fault present

Detection

- Coding
  - space of legal values << space of all values
  - should only see legal
  - *e.g.* parity, ECC (Error Correcting Codes)
- Explicit test (defects, recurring faults)
  - ATPG = Automatic Test Pattern Generation
  - Signature/BIST=Built-In Self-Test
  - POST = Power On Self-Test
- Direct/special access
  - test ports, scan paths

Coping with defects/faults?

- **Key idea:** redundancy
- Detection:
  - Use redundancy to detect error
- Mitigating: use redundant hardware
  - Use spare elements in place of faulty elements (defects)
  - Compute multiple times so can discard faulty result (faults)
  - Exploit Law-of-Large Numbers

Defect Tolerance

Two Models

- Disk Drives (defect map)
- Memory Chips (perfect chip)

Disk Drives

- Expose defects to software
  - software model expects faults
    - Create table of good (bad) sectors
  - manages by masking out in software
    - (at the OS level)
    - Never allocate a bad sector to a task or file
  - yielded capacity varies

Memory Chips

- Provide model in **hardware** of perfect chip
- Model of perfect memory at capacity X
- Use redundancy in hardware to provide perfect model
- Yielded capacity fixed
  - discard part if not achieve

Example: Memory

- Correct memory:
  - N slots
  - each slot reliably stores last value written
- Millions, billions, etc. of bits…
  - have to get them all right?

Memory Defect Tolerance

- Idea:
  - few bits may fail
  - provide more raw bits
  - configure so yield what looks like a perfect memory of specified size

---

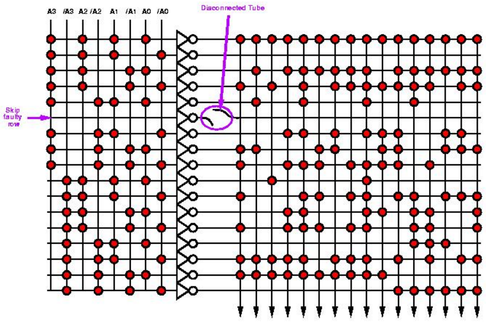
Memory Techniques

- Row Redundancy
- Column Redundancy
- Bank Redundancy

Row Redundancy

- Provide extra rows
- Mask faults by avoiding bad rows
- Trick:
  - have address decoder substitute spare rows in for faulty rows
  - use fuses to program

Spare Row

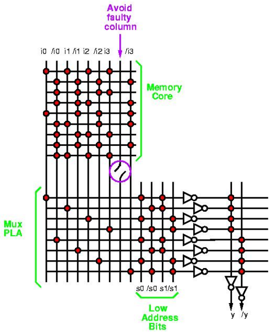


Column Redundancy

- Provide extra columns
- Program decoder/mux to use subset of columns

Spare Memory Column

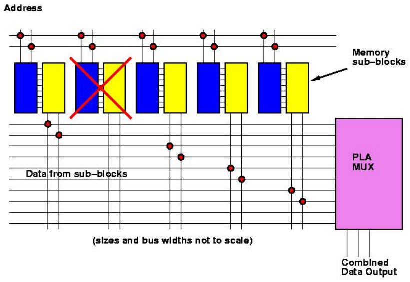
- Provide extra columns
- Program output mux to avoid



Bank Redundancy

- Substitute out entire bank
  - *e.g.* memory subarray
    - include 5 banks
      - only need 4 to yield perfect
    - (N+1 sparing more typical for larger N)

Spare Bank



Yield M of N

- Preclass 4: Probability of yielding 3 of 5 things?
  - Symbolic?
  - Numerical for $P_g=0.9$?

Yield M of N

- P(M of N) = P(yield N)

  + (N choose N-1) P(exactly N-1)

  + (N choose N-2) P(exactly N-2)…

  + (N choose N-M) P(exactly N-M)…

  [think binomial coefficients]

M of 5 example

- $1*P^5 + 5*P^4(1-P)^1+10P^3(1-P)^2+10P^2(1-P)^3+5P^1(1-P)^4 + 1*(1-P)^5$
- Consider P=0.9

– $1*P^5$	0.59	M=5 P(sys)=0.59
– $5*P^4(1-P)^1$	0.33	M=4 P(sys)=0.92
– $10P^3(1-P)^2$	0.07	M=3 P(sys)=0.99
– $10P^2(1-P)^3$	0.008	
– $5P^1(1-P)^4$	0.00045	
– $1*(1-P)^5$	0.00001	

Can achieve higher system yield than individual components!

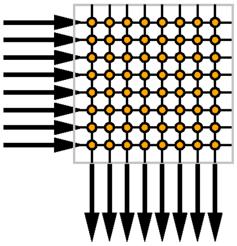
Repairable Area

- Not all area in a RAM is repairable
  - memory bits spare-able
  - io, power, ground, control not redundant

Repairable Area

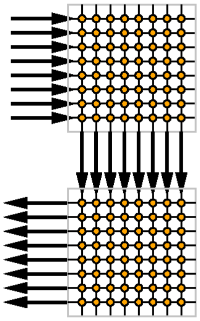
- P(yield) = P(non-repair) * P(repair)
- P(non-repair) = $P^{N_{nr}}$
  - $N_{nr} << N_{total}$
  - $P > P_{repair}$
    - e.g. use coarser feature size
- P(repair) ~ P(yield M of N)

Consider a Crossbar



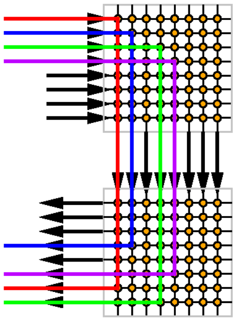
- Allows us to connect any of N things to each other
  - E.g.
    - N processors
    - N memories
    - N/2 processors
    + N/2 memories

Crossbar Buses and Defects



- Two crossbars
- Wires may fail
- Switches may fail
- Provide more wires
  - Any wire fault avoidable
    - M choose N

Crossbar Buses and Defects



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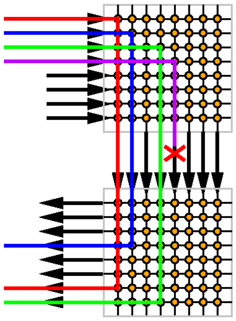
Crossbar Buses and Faults



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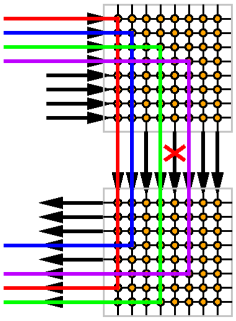
Crossbar Buses and Faults

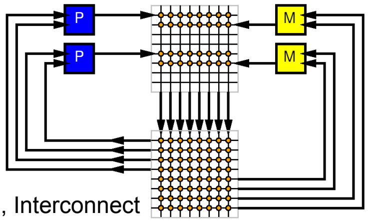
- Two crossbars
- Wires may fail
- Switches may fail

- Provide more wires
  - Any wire fault avoidable
    - M choose N
  - Same idea



Simple System

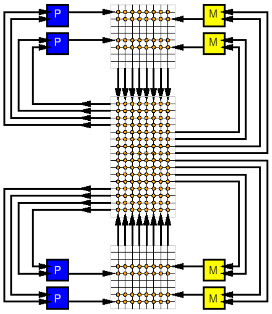
- P Processors
- M Memories
- Wires



Memory, Compute, Interconnect

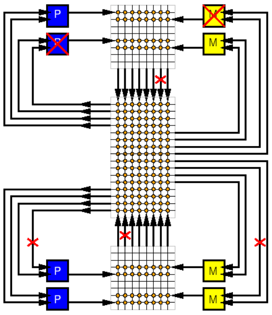
Simple System w/ Spares

- P Processors
- M Memories
- Wires
- Provide spare
  - Processors
  - Memories
  - Wires



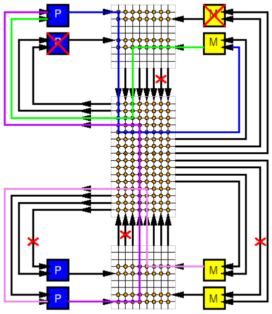
Simple System w/ Defects

- P Processors
- M Memories
- Wires
- Provide spare
  - Processors
  - Memories
  - Wires
- ...and defects



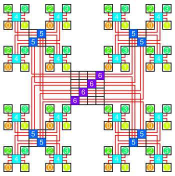
Simple System Repaired

- P Processors
- M Memories
- Wires
- Provide spare
  - Processors
  - Memories
  - Wires
- Use crossbar to switch together good processor and memories



In Practice

- Crossbars are inefficient [Day14-20]
- Use switching networks with
  - Locality
  - Segmentation
- …but basic idea for sparing is the same



Defect Tolerance Questions?

Fault Tolerance

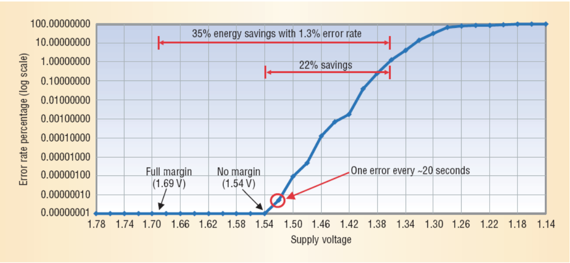
Faults

- Bits, processors, wires
  - May fail during operation
- Basic Idea same:
  - Detect failure using redundancy
  - Correct
- Now
  - Must identify and correct online with the computation

Transient Sources

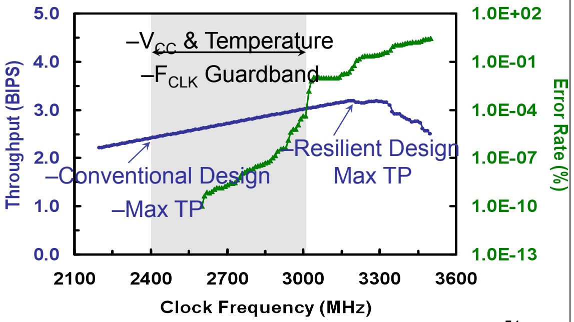
- Effects
  - Thermal noise
  - Timing
  - Ionizing particles
    - α particle 10^5 to 10^6 electrons
    - Calculated gates with 15--30 electrons Day 7
      - Even if CMOS restores, takes time

Voltage and Error Rate



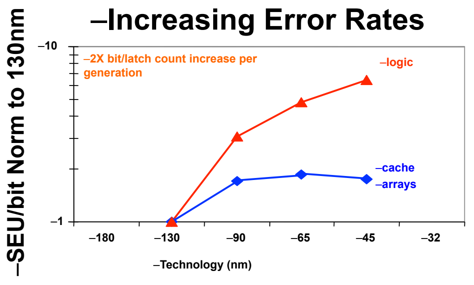
[Austin *et al.--IEEE Computer*, March 2004]

Errors versus Frequency



[Bowman, ISSCC 2008]

Scaling and Error Rates

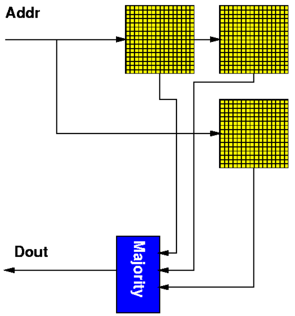


Source: Carter/Intel

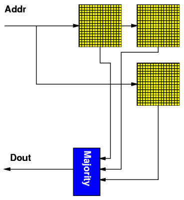
Simple Memory Example

- **Problem:** bits may lose/change value
  - Alpha particle
  - Molecule spontaneously switches
- **Idea:**
  - Store multiple copies
  - Perform majority vote on result

Redundant Memory



Redundant Memory



- Like M-choose-N
- Only fail if >(N-1)/2 faults
- P=0.9
- P(2 of 3)

All good: $(0.9)^3 = 0.729$

+ Any 2 good: $3(0.9)^2(0.1)=0.243$

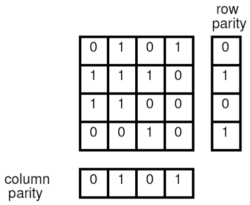
= 0.971

Better: Less Overhead

- Don’t have to keep N copies
- Block data into groups
- Add a small number of bits to detect/correct errors

Row/Column Parity

- Think of NxN bit block as array
- Compute row and column parities
  - (total of 2N bits)



				row parity
0	1	0	1	0
1	1	1	0	1
1	1	0	0	0
0	0	1	0	1
0	1	0	1	column parity

Row/Column Parity

- Think of NxN bit block as array
- Compute row and column parities
  - (total of 2N bits)
- Any single bit error

					row parity
	0	1	0	1	0
	1	1	1	0	1
	1	1	1	0	0
	0	0	1	0	1
column parity	0	1	0	1	

Row/Column Parity

- Think of NxN bit block as array
- Compute row and column parities
  - (total of 2N bits)
- Any single bit error
- By recomputing parity
  - Know which one it is
  - Can correct it

					row parity	
	0	1	0	1	0	0
	1	1	1	0	1	1
	1	1	1	0	0	1
	0	0	1	0	1	1
column parity	0	1	0	1		
	0	1	1	1		

InClass Exercise

- Which Block has an error?
- What correction do we need?

Row/Column Parity

- Simple case is 50% overhead
  - Add 8 bits to 16
  - Better than 200% with 3 copies
  - More expensive than used in practice

					row parity	
	0	1	0	1	0	0
	1	1	1	0	1	1
	1	1	1	0	0	1
	0	0	1	0	1	1
column parity	0	1	0	1		
	0	1	1	1		

In Use Today

- Conventional DRAM Memory systems
  - Use 72b ECC (Error Correcting Code)
  - On 64b words [12.5% overhead]
  - Correct any single bit error
  - Detect multibit errors
- CD blocks are ECC coded
  - Correct errors in storage/reading

RAID

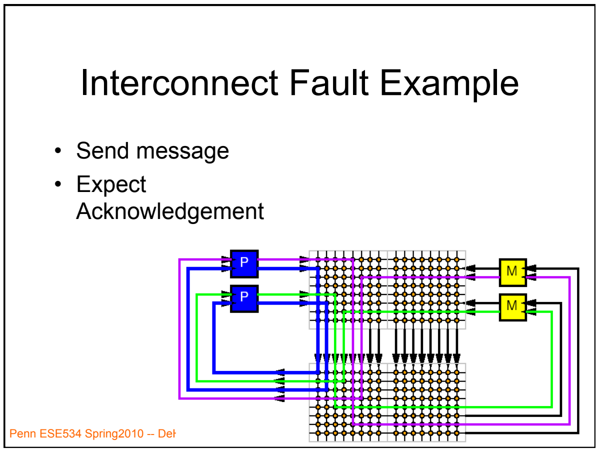
- Redundant Array of Inexpensive Disks
- Disk drives have ECC on sectors
  - At least enough to detect failure
- RAID-5 has one parity disk
  - Tolerate any single disk failure
  - *E.g.* 8-of-9 survivability case
  - With *hot spare*, can rebuild data on spare

Interconnect

- Also uses checksums/ECC
  - Guard against data transmission errors
  - Environmental noise, crosstalk, trouble sampling data at high rates…
- Often just detect error
- Recover by requesting retransmission
  - *E.g.* TCP/IP (Internet Protocols)

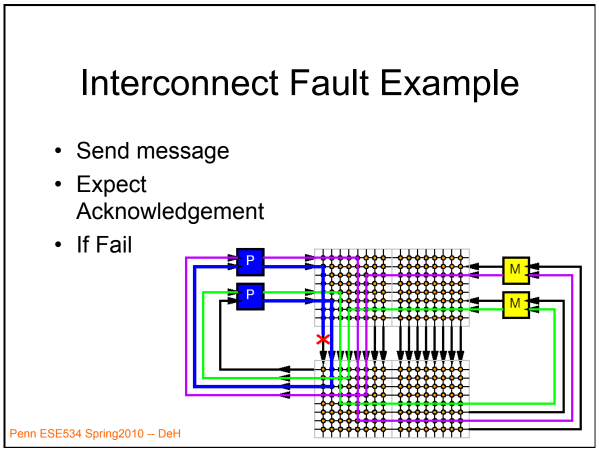
Interconnect

- Also guards against whole path failure
- Sender expects acknowledgement
- If no acknowledgement will retransmit
- If have multiple paths
  - …and select well among them
  - Can route around any fault in interconnect



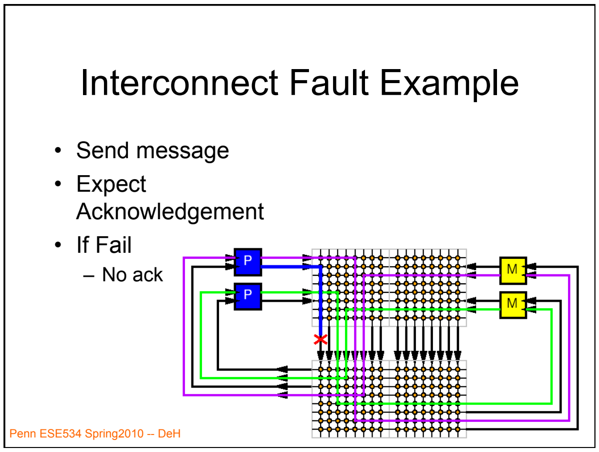
Interconnect Fault Example

- Send message
- Expect Acknowledgement



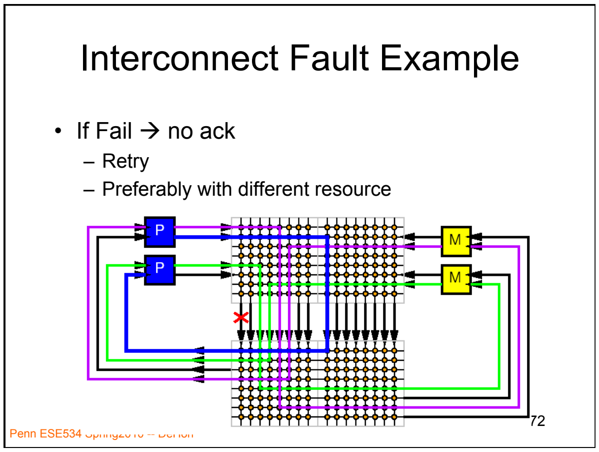
Interconnect Fault Example

- Send message
- Expect Acknowledgement
- If Fail



Interconnect Fault Example

- Send message
- Expect Acknowledgement
- If Fail
  - No ack

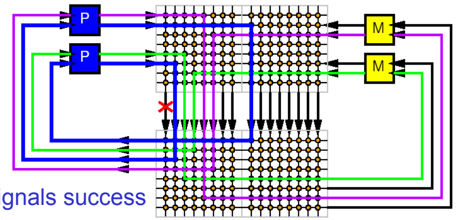


Interconnect Fault Example

- If Fail → no ack
  - Retry
  - Preferably with different resource

Interconnect Fault Example

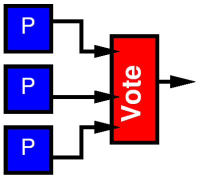
- If Fail → no ack
  - Retry
  - Preferably with different resource



Ack signals success

Compute Elements

- Simplest thing we can do:
  - Compute redundantly
  - Vote on answer
  - Similar to redundant memory



Compute Elements

- Unlike Memory
  - State of computation important
  - Once a processor makes an error
    - All subsequent results may be wrong
- Response
  - “reset” processors which fail vote
  - Go to spare set to replace failing processor

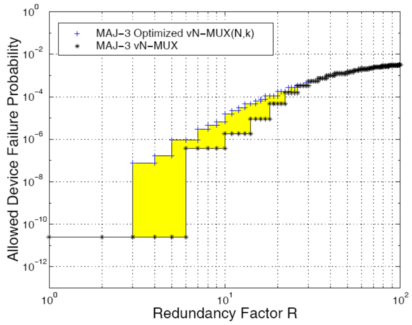
In Use

- NASA Space Shuttle
  - Uses set of 4 voting processors
- Boeing 777
  - Uses voting processors
    - Uses different architectures for processors
    - Uses different software
    - Avoid Common-Mode failures
      - Design errors in hardware, software

Forward Recovery

- Can take this voting idea to gate level
  - VonNeuman 1956
- Basic gate is a majority gate
  - Example 3-input voter
- Alternate stages
  - Compute
  - Voting (restoration)
- Number of technical details…
- High level bit:
  - Requires P_{gate}>0.996
  - Can make whole system as reliable as individual gate

Majority Multiplexing



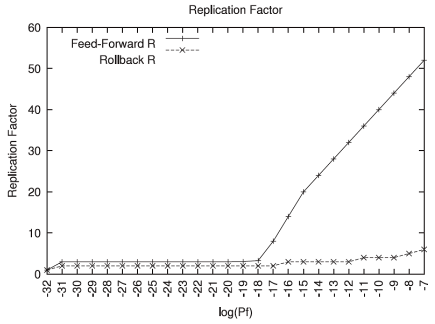
Maybe there’s a better way…

[Roy+Beiu/IEEE Nano2004]

Rollback Recovery

- Commit state of computation at key points
  - to memory (ECC, RAID protected...)
  - …reduce to previously solved problem of protecting memory
- On faults (lifetime defects)
  - recover state from last checkpoint
  - like going to last backup….
  - …(snapshot)

Rollback vs. Forward



Defect vs. Fault Tolerance

- Defect
  - Can tolerate large defect rates (10%)
    - Use virtually all good components
    - Small overhead beyond faulty components
- Fault
  - Require lower fault rate (*e.g.* VN <0.4%)
    - Overhead to do so can be quite large

Summary

- Possible to engineer practical, reliable systems from
  - Imperfect fabrication processes (defects)
  - Unreliable elements (faults)
- We do it today for large scale systems
  - Memories (DRAMs, Hard Disks, CDs)
  - Internet
- …and critical systems
  - Space ships, Airplanes
- Engineering Questions
  - Where invest area/effort?
    - Higher yielding components? Tolerating faulty components?
  - Where do we invoke law of large numbers?
    - Above/below the device level

Admin

- HW5 due Friday
- Reading for Monday 3/15 on web

Big Ideas

- Left to itself:
  - reliability of system << reliability of parts
- Can design
  - system reliability >> reliability of parts [defects]
  - system reliability ~= reliability of parts [faults]
- For large systems
  - must engineer reliability of system
  - …all systems becoming “large”

Big Ideas

- Detect failures
  - – static: directed test
  - – dynamic: use **redundancy** to guard
- Repair with **Redundancy**
- Model
  - – establish and provide model of correctness
    - Perfect component model (memory model)
    - Defect map model (disk drive model)